



FOR IMMEDIATE RELEASE

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AEHR TEST SYSTEMS RECEIVES ADDITIONAL FOX™ ORDER

Fremont, CA (June 4, 2012) - Aehr Test Systems (Nasdaq: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, announced today that it has received an order for an additional FOX-1 system to a leading flash memory manufacturer.

“We are very pleased to have received this follow-on order for additional FOX-1 test capacity, which we believe to be an endorsement of the ongoing cost saving benefits that our customer achieves with our full wafer test solution.” said Carl Buck, vice president of marketing at Aehr Test Systems. “The FOX-1 system, using an Aehr Test Systems’ WaferPak contactor, allows parallel testing of thousands of die on a 300mm wafer with only a single touchdown.

“This order reinforces our belief that the utilization of our worldwide installed base is reaching capacity levels in certain parts of the world for both our FOX wafer test and burn-in solutions as well as our ABTS line of packaged part test and burn-in systems,” added Buck. “It is also a testament to the continued value provided by our FOX-1 system.”

The FOX-1 full wafer parallel test system, a member of the FOX family of wafer level test and burn-in systems, is most effective for test and/or short test during burn-in applications. Other members of Aehr Test’s FOX family of products are focused on long-duration full wafer burn-in and test of products such as automotive ICs, DRAMs and VCSELs (laser diodes).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX family of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak

carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX and WaferPak contactor technologies, acceptance by customers of the WaferPak contactors shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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